

TSMC-02-345

December 15, 2003

To: Commissioner for Patents  
P.O.Box 1450  
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572  
28 Davis Avenue  
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/672,410 09/26/03 |  
Li-Te S. Lin et al.  
A TEST STRUCTURE FOR DIFFERENTIATING  
THE LINE AND VIA CONTRIBUTION IN  
STRESS MIGRATION  
| \_\_\_\_\_ |

#### INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation  
In An Application.

The following Patents and/or Publications are submitted to  
comply with the duty of disclosure under CFR 1.97-1.99 and  
37 CFR 1.56.

#### CERTIFICATE OF MAILING

I hereby certify that this correspondence is being  
deposited with the United States Postal Service as first class  
mail in an envelope addressed to: Commissioner for Patents,  
P.O. Box 1450, Alexandria, VA 22313-1450, on December 19, 2003.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 12/19/03


TSMC-02-345

U.S. Patent 6,342,733 to Hu et al., "Reduced Electro-migration and Stressed Induced Migration of Cu Wires by Surface Coating," describes a test structure for EM and SM.

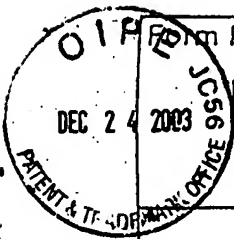
U.S. Patent 6,004,827 to Ryan, "Integrated Circuit Processing," describes various test structures with aluminum runners and overlying dielectrics.

U.S. Patent 5,930,587 to Ryan, "Stress Migration Evaluation Method," describes an SM method and test structure.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a long horizontal flourish extending to the right.

Stephen B. Ackerman,  
Reg. No. 37761



Form PTO-1449

INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION

(Use several sheets if necessary)

Document Number (Sequence)

TSMC-02-345

Application Number

10/672,410

Applicant

Li-Te S. Lin et al.

Filing Date

09/26/03

Group Art Unit

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILED DATE IF APPROPRIATE
	6342733	1/29/02	Hu et al.	257	750	7/27/99
	6004827	12/21/99	Ryan	438	6	9/3/97
	5930587	7/27/99	Ryan	438	14	8/27/97

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.